PATENT 4303-1009

#### IN THE U.S. PATENT AND TRADEMARK OFFICE

In re application of

Harald KRAUS et al.

Conf.

Application No. NEW NATIONAL PHASE

Group

Filed August 8, 2006

Examiner

METHOD FOR SELECTIVE ETCHING

# INFORMATION DISCLOSURE STATEMENT (SUBMISSION CONCURRENT WITH THE FILING OF A NEW PATENT APPLICATION)

Assistant Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

August 8, 2006

Sir:

Pursuant to 37 C.F.R. §§ 1.97 and 1.98, and in fulfillment of the duty of disclosure under 37 C.F.R. § 1.56, applicant(s) hereby submit(s) an Information Disclosure Statement for consideration by the Examiner.

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The patents, publications, or other information submitted for consideration by the Office are listed on PTO-1449, attached hereto.

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- Copies of the U.S. patents or publications are not submitted since the USPTO has waived their submission for applications filed after June 30, 2003.
- Submitted herewith is a legible copy of (i) each foreign patent; (ii) each publication or that portion which caused it to be listed; and (iii) all other information or that portion which caused it to be listed.
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## 0/588766 CONCISE EXPLANATION OF THE RELEVANCE REC'D PCT/PTO 08 AUG 2006 (Check at least one box) API Rec'd PCT/PTO 08 AUG 2006 DOCUMENTS IN THE ENGLISH LANGUAGE 図 а. The non U.S. patents, non U.S. patent application publications, foreign publications, or other information in the English language do not require a statement of relevancy. DOCUMENTS NOT IN THE ENGLISH LANGUAGE b. П A concise explanation of the relevance of all patents, publications, or other information listed that is not in the English language is as follows: FOREIGN SEARCH REPORT OR ACTION $\boxtimes$ c. An English language version of the search report or action that indicates the degree of relevance found by the foreign office is attached, thereby requirement satisfying the for а explanation. See MPEP 609(A)(3). OTHER d. The following additional information is provided for the Examiner's consideration. FEES This Information Disclosure Statement is being filed concurrently with the filing of a new patent application; therefore, no fee is required. If The Examiner has any questions concerning this IDS, he/she is requested to contact the undersigned. Respectfully submitted, YOUNG & THOMPSON Casto Benoit Castel, Reg. No. 35,041 745 South 23<sup>rd</sup> Street

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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

\* English language abstract provided for the Examiner's convenience

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